INTEGRATED CIRCUITS

DATA SHEET

GTL16612
18-bit GTL/GTL+ to LVTTL/TTL
bidirectional latched translator (3-State)

Product specification





18-bit GTL/GTL⁺ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

FEATURES

- 18-bit bidirectional bus interface
- Translates between GTL/GTL+ logic levels (B ports) and LVTTL/TTL logic levels (A ports)
- 5 V I/O tolerant on the LVTTL/TTL side (A ports)
- No bus current loading when LVTTL/TTL output is tied to 5 V bus
- 3-State buffers
- Output capability: +64 mA/-32 mA on the LVTTL/TTL side (A ports); +40 mA on the GTL side (B ports)
- TTL input levels on control pins
- Power-up reset
- Power-up 3-State
- Positive edge triggered clock inputs
- Latch-up protection exceeds 500 mA per JESD78
- ESD protection exceeds 2000 V HBM per JESD22-A114, 200 V MM per JESD22-A115 and 1000 V CDM per JESD22-C101

DESCRIPTION

The GTL16612 is a high-performance BiCMOS product designed for V_{CC} operation at 3.3 V with I/O compatibility up to 5 V.

This device is an 18-bit universal transceiver featuring non-inverting 3-State bus compatible outputs in both send and receive directions. Data flow in each direction is controlled by output enable (OEAB and OEBA), latch enable (LEAB and LEBA), and clock (CPAB and CPBA) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is High. When LEAB is Low, the A data is latched if CPAB is held at a High or Low logic level. If LEAB is Low, the A-bus data is stored in the latch/flip-flop on the Low-to-High transition of CPAB. When OEAB is Low, the outputs are active. When OEAB is High, the outputs are in the high-impedance state. The clocks can be controlled with the clock-enable inputs (CEBA/CEAB).

Data flow for B-to-A is similar to that of A-to-B but uses $\overline{\text{OEBA}}$, LEBA and CPBA.

QUICK REFERENCE DATA

CVMDOL	DADAMETED	CONDITIONS	TYPICAL	LINUT
SYMBOL	PARAMETER	T _{amb} = 25°C 3.3 V		UNIT
t _{PLH} t _{PHL}	Propagation delay An to Bn or Bn to An	C _L = 50 pF	1.9	ns
C _{IN}	Input capacitance (Control pins)	$V_I = 0 \text{ V or } V_{CC}$	4	pF
C _{I/O}	I/O pin capacitance	Outputs disabled; $V_{I/O} = 0 \text{ V or } V_{CC}$	8	pF
I _{CCZ}	Total supply current	Outputs disabled	12	mA

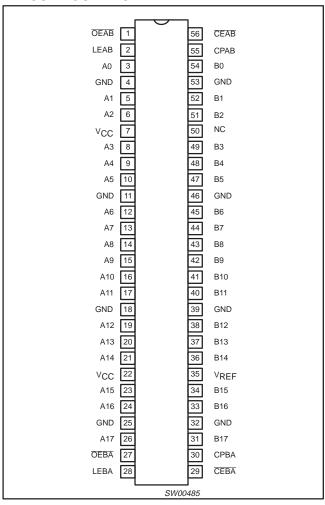
ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	ORDER CODE	DWG NUMBER
56-Pin Plastic TSSOP Type II	−40°C to +85°C	GTL16612 DGG	SOT364-1

18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

PIN CONFIGURATION



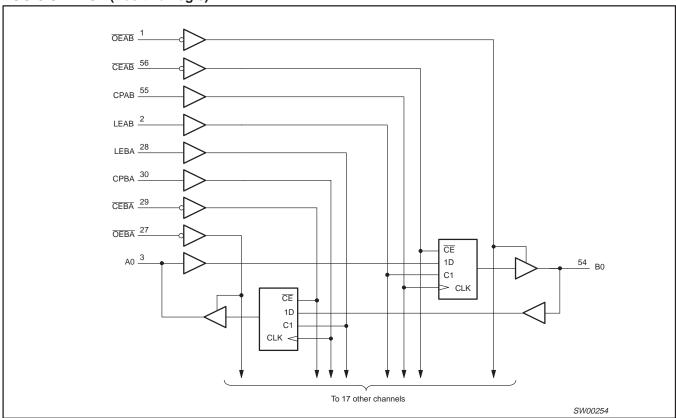
PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
1, 27	OEAB/OEBA	A-to-B/ B-to-A Output enable input (active Low)
29, 56	CEBA/CEAB	B-to-A/A-to-B clock enable
2, 28	LEAB/LEBA	A-to-B/B-to-A Latch enable input
55,30	CPAB/CPBA	A-to-B/B-to-A Clock input (active rising edge)
3, 5, 6, 8, 9, 10, 12, 13, 14, 15, 16, 17, 19, 20, 21, 23, 24, 26	A0-A17	Data inputs/outputs (A side)
54, 52, 51, 49, 48, 47, 45, 44, 43, 42, 41, 40, 38, 37, 36, 34, 33, 31	B0-B17	Data inputs/outputs (B side)
4, 11, 18, 25, 32, 39, 46, 53	GND	Ground (0 V)
7, 22	V _{CC}	Positive supply voltage
35	V_{REF}	GTL reference voltage
50	NC	No connection

18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

LOGIC SYMBOL (Positive Logic)



FUNCTION TABLE

	INPUTS							
CEAB ¹	OEAB ¹	В						
Х	Н	Х	Х	Х	Z			
Х	L	Н	Х	L	L			
Х	L	Н	Х	Н	Н			
Н	L	L	Х	Х	B _O ²			
Н	L	L	Х	Х	B _O ²			
L	L	L	↑	L	L			
L	L	L	↑	Н	Н			
L	L	L	Н	Х	B_0^2 B_0^3			
L	L	L	L	Х	B _O ³			

- X = Don't care
- H = High voltage level
- L = Low voltage level
- \uparrow = Low to High
- Z = High impedance "off" state
- 1. A-to-B data flow is shown: B-to-A flow is similar but uses $\overline{\text{OEBA}}$, LEBA, CPBA, and $\overline{\text{CEBA}}$.
- 2. Output level before the indicated steady-state input conditions were established.
- 3. Output level before the indicated steady-state input conditions were established, provided that CPAB was Low before LEAB went Low.

18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

ABSOLUTE MAXIMUM RATINGS 1, 2

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +4.6	V
I _{IK}	DC input diode current	V _I < 0	-50	mA
. V.	DC input voltage ³	A port	-0.5 to +7.0	V
V _I	DC input voitage	B port	-0.5 to +4.6	V
lok	DC output diode current V _O < 0; A port		-50	mA
V	DC output voltore3	Output in Off or High state; A port	-0.5 to +7.0	V
Vo	DC output voltage ³	Output in Off or High state; B port	-0.5 to +4.6	V
	Current into any output in the LOW state	A port	128	mA
l _{OL}	Current into any output in the LOW state	B port		mA
I _{OH}	Current into any output in the HIGH state	A port	-64	mA
T _{stg}	Storage temperature range		-65 to +150	°C

NOTES

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	TEST CONDITIONS	3.3 V RAN	GE LIMITS	UNIT
STWIBUL	FANAMETER	TEST CONDITIONS	MIN	MAX	JUNII
V _{CC}	DC supply voltage		3.0	3.6	V
V	Towningtion voltage	GTL	1.14	1.26	V
V _{TT}	Termination voltage	GTL+	1.35	1.65	1 °
	CTI reference voltege	GTL	0.74	0.87	V
V_{REF}	GTL reference voltage	GTL+	0.9	1.10	1 °
M	Input voltage	B port	0	V _{TT}	V
VI		Except B port	Except B port	0	5.5
V	LUCI level input veltere	B port	V _{REF} +50 mV		V
V_{IH}	HIGH-level input voltage	Except B port	2.0		1 '
	LOW level input valtage	B port		V _{REF} -50 mV	V
V_{IL}	LOW-level input voltage	Except A port		0.8	1 '
I _{OH}	HIGH-level output current	A port		-32	mA
	LOW love of contrast comment	B port		40	A
l _{OL}	LOW-level output current	A port		64	mA
T _{amb}	Operating free-air temperature range		-40	+85	°C

^{1.} Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

^{3.} The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

DC ELECTRICAL CHARACTERISTICS (3.3 V \pm 0.3 V RANGE)

	SYMBOL PARAMETER					LIMITS		
SYMBOL			TEST CONDIT	TIONS	Temp = -	-40°C to	+85°C	UNIT
					MIN	TYP ¹	MAX	
V _{IK}	Input clamp vo	ltage	$V_{CC} = 3.0 \text{ V}; I_{IK} = -18 \text{ mA}$			-0.85	-1.2	V
	LP ab last at a set		$V_{CC} = 3.0 \text{ to } 3.6 \text{ V}; I_{OH} = -100 \mu\text{A}$	A	V _{CC} -0.2	V _{CC}		V
V_{OH}	High-level outp	out voltage	$V_{CC} = 3.0 \text{ V}; I_{OH} = -32 \text{ mA}$	A port	2.0	2.3		\ \ \
			$V_{CC} = 3.0 \text{ V}; I_{OL} = 100 \mu\text{A}$			0.07	0.2	
			V _{CC} = 3.0 V; I _{OL} = 16 mA	1		0.25	0.4] ,
V_{OL}	Low-level outp	out voltage	V _{CC} = 3.0 V; I _{OL} = 32 mA	A port		0.3	0.5	\ \ \
			V _{CC} = 3.0 V; I _{OL} = 64 mA	1		0.4	0.55	
			V _{CC} = 3.0 V; I _{OL} = 40 mA	B port		0.4	0.5	V
			$V_{CC} = 3.6 \text{ V}; V_I = V_{CC} \text{ or GND}$	O a strat o ' a a		0.1	±1	
			V _{CC} = 0 or 3.6 V; V _I = 5.5 V	Control pins		0.1	10	μΑ
	<u> </u>	put leakage current			0.1	20		
II.	I _I Input leakage of		$V_{CC} = 3.6 \text{ V}; V_{I} = V_{CC}$	I/O Data pins ⁴ A port		0.5	10	μΑ
			V _{CC} = 3.6 V; V _I = 0	1		0.1	-5	
			$V_{CC} = 3.6 \text{ V}; V_I = V_{TT} \text{ or GND}$	B port			±5	μΑ
I _{OFF}	Output off curre	ent	$V_{CC} = 0 \text{ V}; V_{I} \text{ or } V_{O} = 0 \text{ to } 4.5 \text{ V}$			0.1	±100	μА
	Des Haldania		V _{CC} = 3 V; V _I = 0.8 V		75	130		_
HOLD	Bus Hold curre	ent, A outputs	V _{CC} = 3 V; V _I = 2.0 V		-75	-140		μΑ
I _{EX}	Current into an High state whe		V _O = 5.5 V; V _{CC} = 3.0 V	A port		10	125	μА
I _{PU/PD}	Power up/dowi		$V_{CC} \le 1.2 \text{ V}; V_O = 0.5 \text{ V to } V_{CC}; V$ $\overline{OE} = \text{Don't care}$	= GND or V _{CC}		1.0	±100	μА
I _{CCH}			Outputs high			5.0	9.0	
I _{CCL}	A-Port		Outputs low	1		10.5	18.5	1
I _{CCZ} ⁵		V _{CC} = 3.6 V	Disabled	$V_I = GND \text{ or } V_{CC_i} I_O = 0$		6.0	11.5	mA
I _{CCH}		1	Outputs high	1		9.7	17.5	
I _{CCL}	B-Port		Outputs low	1		7.0	12.0	
Δl _{CC}	Additional supplinput pin ²	oly current per	V _{CC} = 3 V to 3.6 V; One input at V Other inputs at V _{CC} or GND	CC-0.6 V,		0.04	0.2	mA

- All typical values are at V_{CC} = 3.3 V and T_{amb} = 25°C.
 This is the increase in supply current for each LVTTL input at the specified voltage level other than V_{CC} or GND
 This parameter is valid for any V_{CC} between 0 V and 1.2 V with a transition time of up to 10 msec. From V_{CC} = 1.2 V to V_{CC} = 3.3 V ± 0.3 V a transition time of 100 µsec is permitted. This parameter is valid for T_{amb} = 25°C only.
- 4. Unused pins at V_{CC} or GND.
- 5. I_{CCZ} is measured with outputs pulled up to V_{CC} or pulled down to ground.

18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

AC CHARACTERISTICS (A PORT)

GND = 0 V; t_r = t_f = 2.5 ns; C_L = 50 pF; R_L = 500 Ω ; T_{amb} = -40°C to +85°C.

				GTL		GTL+			
	GTL16612 An Port			c = 3.3 V ±0.	3 V	V_{CC} = 3.3 V ±0.3 V			1
			,	V _{REF} = 0.8 V	/	,	/ _{REF} = 1.0 \	/	UNIT
SYMBOL	PARAMETER	WAVEFORM	MIN	TYP ¹	MAX	MIN	TYP ¹	MAX]
t _{PLH}	Bn to An	2	1.6	3.0	5.0	1.6	3.0	5.0	ns
t _{PHL}	Bn to An	2	3.0	4.9	6.3	3.0	4.9	6.3	ns
t _{PLH}	LEBA to An	3	1.6	2.7	4.2	1.6	2.7	4.2	ns
t _{PHL}	LEBA to An	3	1.6	2.8	4.3	1.6	2.8	4.3	ns
t _{PLH}	CPBA to An	1	1.9	3.4	4.7	1.9	3.4	4.7	ns
t _{PHL}	CPBA to An	1	1.8	3.8	5.2	1.8	3.8	5.2	ns
t _{PZH}	OEBA to An	5	1.5	2.6	4.2	1.5	2.6	4.2	ns
t _{PHZ}	OEBA to An	5	1.4	2.9	4.8	1.4	2.9	4.8	ns
t _{PZL}	OEBA to An	6	1.3	2.4	3.8	1.3	2.4	3.8	ns
t _{PLZ}	OEBA to An	6	1.2	2.2	3.5	1.2	2.2	3.5	ns

NOTE:

AC CHARACTERISTICS (B PORT)

GND = 0 V; $t_r = t_f = 2.5$ ns; $C_L = 30$ pF; $R_L = 25$ Ω ; $T_{amb} = -40$ °C to +85°C.

		GTL		GTL+					
	GTL16612 Bn Port			c = 3.3 V ±0.	3 V	V_{CC} = 3.3 V ±0.3 V			1
			,	V _{REF} = 0.8 V	1	١	/ _{REF} = 1.0 V	1	UNIT
SYMBOL	PARAMETER	WAVEFORM	MIN	TYP ¹	MAX	MIN	TYP ¹	MAX	
t _{PLH}	An to Bn	2	1.4	2.4	3.7	1.3	2.4	3.7	ns
t _{PHL}	An to Bn	2	1.3	2.5	4.0	1.4	2.6	4.2	ns
t _{PLH}	LEAB to Bn	3	1.7	3.0	4.4	1.8	3.0	4.6	ns
t _{PHL}	LEAB to Bn	3	2.1	3.5	5.4	2.3	3.6	5.5	ns
t _{PLH}	CPAB to Bn	1	1.8	3.1	4.5	1.9	3.1	4.8	ns
t _{PHL}	CPAB to Bn	1	2.3	3.6	5.4	2.4	3.8	5.8	ns
t _{PLH}	OEAB to Bn	7	1.1	2.1	3.3	1.4	2.0	3.5	ns
t _{PHL}	OEAB to Bn	7	1.6	2.8	4.4	1.0	2.9	4.5	ns

NOTE:

^{1.} Typical values are at V_{CC} = 3.3 V, T_{amb} = +25°C.

^{1.} Typical values are at V_{CC} = 3.3 V, T_{amb} = +25°C.

18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

AC SETUP REQUIREMENTS (3.3 V \pm 0.3 V RANGE)

A Port: GND = 0 V; Input $t_r = t_f = 2.5$ ns; $C_L = 50$ pF; $R_L = 500~\Omega$; $T_{amb} = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$; $V_{REF} = 0.8$ V or 1.0 V. B Port: GND = 0 V; Input $t_r = t_f = 2.5$ ns; $C_L = 30$ pF; $R_L = 25~\Omega$; $V_{REF} = 0.8$ V or 1.0 V.

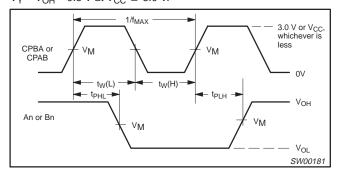
			LIN	MITS	
SYMBOL	PARAMETER	WAVEFORM	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		UNIT
			MIN	MAX	1
t _s (H)	Setup time, High or Low	4	1.5		ns
t _s (L)	Bn to CPBA	4	1.5		ns
t _s (H)	Setup time, High or Low	4	2.0		ns
t _s (L)	An to CPAB	4	3.0		ns
t _h (H)	Hold time, High or Low	4	1.0		ns
t _h (L)	Bn to CPBA, or An to CPAB	4	1.0		ns
t _s (H)	Setup time, High or Low	4	1.0		ns
t _s (L)	Bn to LEBA, or An to LEAB	4	1.0		ns
t _h (H)	Hold time, High or Low	4	1.5		ns
t _h (L)	Bn to LEBA, or An to LEAB	4	1.5		ns
t _s (H)	Setup time, High or Low	4	1.0		ns
t _s (L)	CEAB to CPAB, or CEBA to CPBA	4	1.0		ns
t _h (H)	Hold time, High or Low	4	1.5		ns
t _h (L)	CEAB to CPAB, or CEBA to CPBA	4	1.0		ns
t _w (H)	Pulse width, High or Low	4	2.0		ns
t _w (L)	CPBA or CPAB	4	2.0		ns
t _w (H)	Pulse width, High LEBA or LEAB	3	1.5		ns

18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

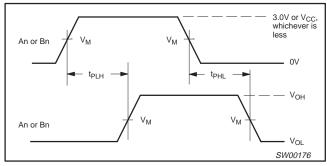
GTL16612

AC WAVEFORMS

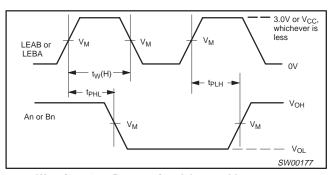
 V_M = 1.5 V at $V_{CC} \ge 3.0$ V. V_M = 1.5 V for A ports and control pins; V_M = 0.8 V for B ports in GTL mode; V_M = 1.0 V for B ports in GTL+ mode. $V_X = V_{OL} + 0.3$ V at $V_{CC} \ge 3.0$ V. $V_Y = V_{OH} - 0.3$ V at $V_{CC} \ge 3.0$ V.



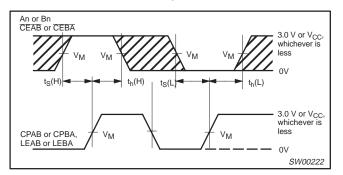
Waveform 1. Propagation delay, clock input to output, clock pulse width, and maximum clock frequency



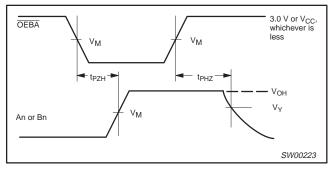
Waveform 2. Propagation delay, transparent mode



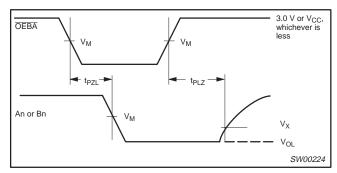
Waveform 3. Propagation delay, enable to output, and enable pulse width



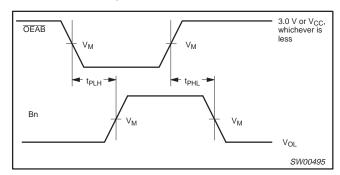
Waveform 4. Data setup and hold times



Waveform 5. 3-State output enable time to high level and output disable time from high level



Waveform 6. 3-State output enable time to low level and output disable time from low level

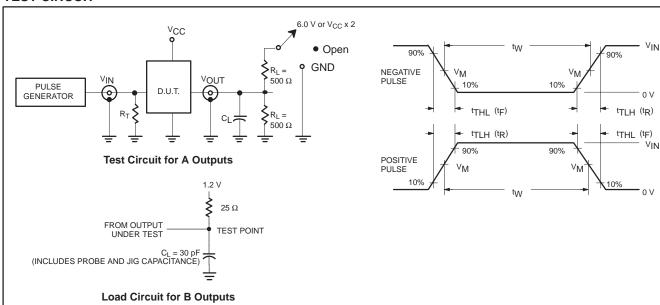


Waveform 7. Output enable time on open collector output with pullup

18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

TEST CIRCUIT



SWITCH POSITION

TEST	SWITCH
t _{PLZ} /t _{PZL}	6 V
t _{PLH} /t _{PHL}	Open
t _{PHZ} /t _{PZH}	GND

DEFINITIONS

R_L = Load resistor; see AC CHARACTERISTICS for value.

 $C_L = Load$ capacitance includes jig and probe capacitance: See AC CHARACTERISTICS for value.

	INPUT PULSE REQUIREMENTS								
FAMILY	Amplitude	Rep. Rate	t _W	t _R	t _F				
74GTL16	3.0 V or V _{CC} whichever is less	≤10 MHz	500 ns	≤2.5 ns	≤2.5 ns				

SW00255

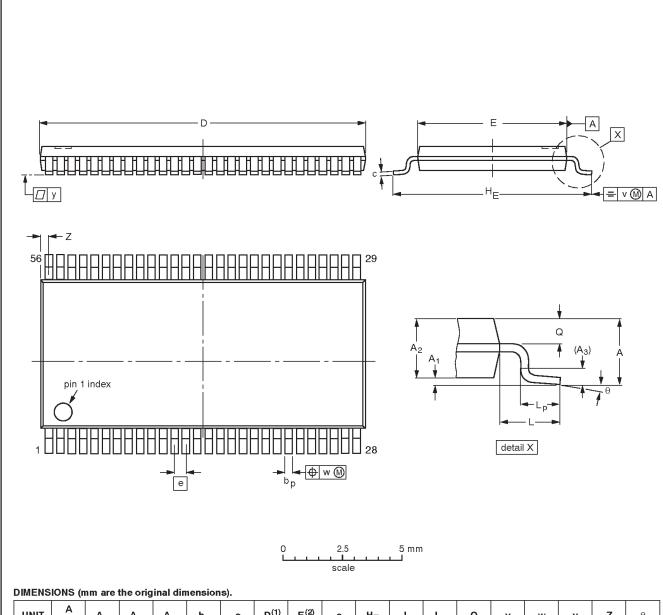
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18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

TSSOP56: plastic thin shrink small outline package; 56 leads; body width 6.1mm

SOT364-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽²⁾	е	HE	L	Lp	Q	٧	w	у	z	θ
mm	1.2	0.15 0.05	1.05 0.85	0.25	0.28 0.17	0.2 0.1	14.1 13.9	6.2 6.0	0.5	8.3 7.9	1.0	0.8 0.4	0.50 0.35	0.25	0.08	0.1	0.5 0.1	8° 0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	RENCES		EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	1330E DATE
SOT364-1		MO-153EE				-93-02-03 95-02-10

18-bit GTL/GTL+ to LVTTL/TTL bidirectional latched translator (3-State)

GTL16612

Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

^[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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